

**RF POWER MOSFET** 

N-CHANNEL PUSH - PULL PAIR

**Common Source** ARF476FI Push-Pull Pair G 165V 450W 150MHz

The ARF476FL is a matched pair of RF power transistors in a common source configuration. It is designed for high voltage push-pull or parallel operation in narrow band ISM and MRI power amplifiers up to 150 MHz.

- Specified 150 Volt, 128 MHz Characteristics:
  - **Output Power = 900 Watts Peak** 
    - Gain = 15dB (Class AB)

Efficiency = 50% min

- Extended Flange 3mm Creep Distance.
- High Voltage Breakdown and Large SOA for Superior Ruggedness.
- Low Thermal Resistance.

MAXIMUN	I RATINGS All Ratings: T <sub>C</sub>	= 25°C unless otherwise s	specified.
Symbol	Parameter	ARF476FL	UNIT
V <sub>DSS</sub>	Drain-Source Voltage	500	Valta
V <sub>DGO</sub>	Drain-Gate Voltage	500	Volts
Ι <sub>D</sub>	Continuous Drain Current @ T <sub>C</sub> = 25°C (each device)	10	Amps
V <sub>GS</sub>	Gate-Source Voltage	±30	Volts
P <sub>D</sub>	Total Device Dissipation @ T <sub>C</sub> = 25°C	910	Watts
T <sub>J</sub> ,T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55 to 175	°C
TL	Lead Temperature: 0.063" from Case for 10 Sec.	300	

# STATIC ELECTRICAL CHARACTERISTICS (each device)

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage ( $V_{GS} = 0V, I_{D} = 250 \mu A$ )	500			Volts
V <sub>DS(ON)</sub>	On State Drain Voltage <sup>(1)</sup> ( $I_{D(ON)} = 5A, V_{GS} = 10V$ )		2.9	4	VOItS
	Zero Gate Voltage Drain Current (V <sub>DS</sub> = V <sub>DSS</sub> , V <sub>GS</sub> = 0V)			100	
DSS	Zero Gate Voltage Drain Current ( $V_{DS} = 50V, V_{GS} = 0, T_{C} = 125^{\circ}C$ )			500	μA
I <sub>GSS</sub>	Gate-Source Leakage Current ( $V_{GS} = \pm 30V$ , $V_{DS} = 0V$ )			±100	nA
9 <sub>fs</sub>	Forward Transconductance ( $V_{DS} = 15V, I_{D} = 5A$ )	3	3.6		mhos
g <sub>fs1</sub> /g <sub>fs2</sub>	Forward Transconductance Match Ratio ( $V_{DS} = 15V$ , $I_{D} = 5A$ )	0.9		1.1	
V <sub>GS(TH)</sub>	Gate Threshold Voltage ( $V_{DS} = V_{GS}$ , $I_{D} = 200$ mA)	2	3.3	4	Valta
$\Delta V_{GS(TH)}$	Gate Threshold Voltage Match ( $V_{DS} = V_{GS}$ , $I_{D} = 200$ mA)			0.2	Volts

# THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	ТҮР	MAX	UNIT
$R_{_{ ext{ heta}JC}}$	Junction to Case		0.15	0.165	°C / M
$R_{_{ extsf{ heta}JHS}}$	Junction to Sink (Use High Efficiency Thermal Grease and Planar Heat Sink Surface.)		0.30	0.33	°C/W

🟹 🙏 CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

## DYNAMIC CHARACTERISTICS (per section)

Symbol	Characteristic	Test Conditions	MIN	ТҮР	МАХ	UNIT
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V		780	830	
C <sub>oss</sub>	Output Capacitance	$V_{\rm DS} = 50V$		125	130	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1MHz		7	9	
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>GS</sub> = 15V		5.1	10	
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 250V		4.1	8	ns
t <sub>d(off)</sub>	Turn-off Delay Time	I <sub>D</sub> = I <sub>D[Cont.]</sub> @ 25°C		12	18	115
t <sub>f</sub>	Fall Time	$R_{G} = 1.6 \Omega$		4.0	7	

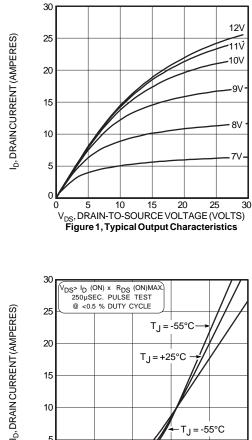
## FUNCTIONAL CHARACTERISTICS (Push-Pull Configuration)

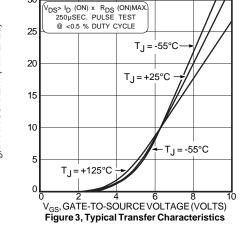
Symbol	Characteristic	Test Conditions	MIN	ТҮР	МАХ	UNIT
G <sub>PS</sub>	Common Source Amplifier Power Gain	f = 128 MHz Idq = 15mA V <sub>DD</sub> = 150V	14	16		dB
η	Drain Efficiency	$P_{out} = 900W$	50	55		%
ψ	Electrical Ruggedness VSWR 5:1	PW = 3ms 10% duty cycle	No Degradation in Output Power			

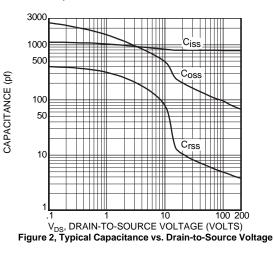
(1) Pulse Test: Pulse width < 380  $\mu$ S, Duty Cycle < 2%.

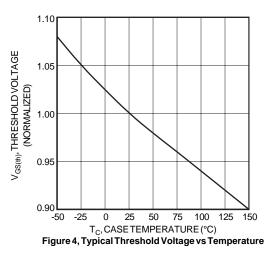
Microsemi Reserves the right to change, without notice, the specifications and information contained herein.

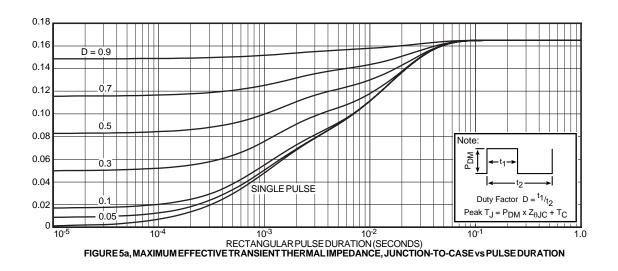
Per transistor section unless otherwise specified.











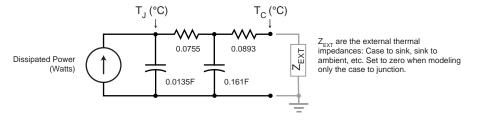
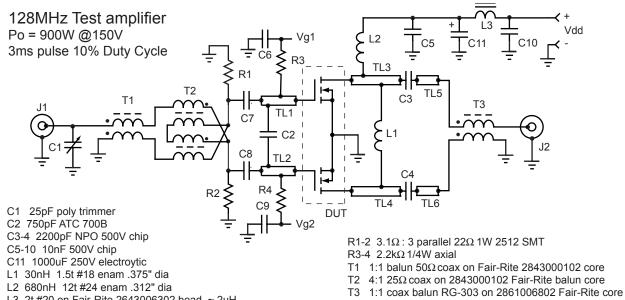


Figure 5b, TRANSIENT THERMAL IMPEDANCE MODEL

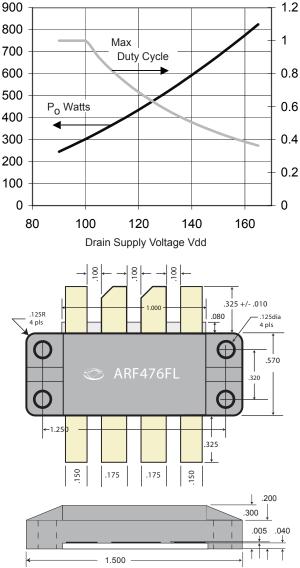
Table 1 - Typical Series Equivalent Large Signal Input - Output Impedance

Freq. (MHz)	$Z_{in}$ ( $\Omega$ ) gate to gate	$Z_{OL}(\Omega)$ drain - drain
30 60 90 120	5.2 -j10 1.37 -j5.2 .53 -j2.6 .25 -j1.0	41 -j20 26 -j25 16 -j23 10 -j20
150	.25 +j0.2	6.7 -j17

 $Z_{in}$  - Gate -gate shunted with  $25 \Omega$   $~I_{DQ}$  = 15mA each side  $Z_{\text{OL}}$  - Conjugate of optimum load for 600 Watts peak output at  $V_{dd}$  = 150V 25% duty cycle and PW = 5ms



L3 2t #20 on Fair-Rite 2643006302 bead, ~ 2uH



Peak Output Power vs. Vdd and Duty Cycle

- T1 1:1 balun 50Ω coax on Fair-Rite 2843000102 core
- 4:1 25Ω coax on 2843000102 Fair-Rite balun core
- TL1-2 Printed line L= 0.75" w =.23"
- TL3-6 Printed line L= 0.65" w =.23"

0.23" wide stripline on FR-4 board is ~  $30\&!Z_0$ 

Notes:

The value of L1 must be adjusted as the supply voltage is changed to maintain resonance in the output circuit. At 128MHz its value changes from approximately 40nH at 100V to 30nH at 150V.

With the  $50\Omega$  drain-to-drain load, the duty cycle above 100V must be reduced to insure power dissipation is within the limits of the device. Maximum pulse length should be 100mS or less. See transient thermal impedance, figure 5.

#### Thermal Considerations and Package Mounting:

The rated power dissipation is only available when the package mounting surface is at 25°C and the junction temperature is 175°C The thermal resistance between junctions and case mounting surface is 0.16°C/W. When installed, an additional thermal impedance of 0.15°C/W between the package base and the mounting surface is typical. Insure that the mounting surface is smooth and flat. Thermal joint compound must be used to reduce the effects of small surface irregularities. Use the minimum amount necessary to coat the surface. The heatsink should incorporate a copper heat spreader to obtain best results.

The package design clamps the ceramic base to the heatsink. A clamped joint maintains the required mounting pressure while allowing for thermal expansion of both the base and the heat sink. Four 4-40 (M3) screws provide the required mounting force. T = 6in-lb (0.68 N-m).

> HAZARDOUS MATERIAL WARNING The white ceramic portion of the device between leads and mounting surface is beryllium oxide, BeO. Beryllium oxide dust is toxic when inhaled. Care must be taken during handling and mounting to avoid damage to this area. These devices must never be thrown away with general industrial or domestic waste.

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